

March 2008

FDMA1028NZ

Dual N-Channel PowerTrench® MOSFET

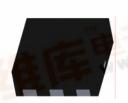
General Description

This device is designed specifically as a single package solution for dual switching requirements in cellular handset and other ultra-portable applications. It features two independent N-Channel MOSFETs with low on-state resistance for minimum conduction losses. The MicroFET 2x2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.

Features

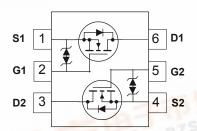
- 3.7 A, 20V. $R_{DS(ON)} = 68 \text{ m}\Omega @ V_{GS} = 4.5V$ $R_{DS(ON)} = 86 \text{ m}\Omega @ V_{GS} = 2.5V$
- Low profile 0.8 mm maximum in the new package MicroFET 2x2 mm
- HBM ESD protection level > 2kV (Note 3)
- RoHS Compliant







MicroFET 2x2



Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter	e-//(6	Ratings	Units
V _{DS}	Drain-Source Voltage		20	V
V _{GS}	Gate-Source Voltage		±12	V
100	Drain Current - Continuous	(Note 1a)	3.7	A
ID	- Pulsed		6	
P _D	Power Dissipation for Single Operation	(Note 1a)	1.4	W
		(Note 1b)	0.7	- 17.0
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	86 (Single Operation)		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	173 (Single Operation)	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1c)	69 (Dual Operation)	C/VV	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1d)	151 (Dual Operation)		

Package Marking and Ordering Information

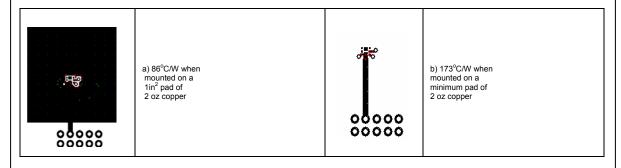
Device Marking	Device	Reel Size	Tape width	Quantity
028	FDMA1028NZ	7"	8mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		15		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V			1	μА
I _{GSS}	Gate-Body Leakage	V _{GS} = ± 12 V, V _{DS} = 0 V			±10	μА
On Chara	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	0.6	1.0	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-4		mV/°C
$R_{\text{DS(on)}}$	Static Drain–Source On–Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 3.7 \text{ A}$ $V_{GS} = 2.5 \text{ V}, I_D = 3.3 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 3.7 \text{ A}, T_J = 125 ^{\circ}\text{C}$		37 50 53	68 86 90	mΩ
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_{D} = 3.7 \text{ A}$		16		S
Dvnamic	Characteristics				•	•
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$		340		pF
Coss	Output Capacitance	f = 1.0 MHz		80		pF
C _{rss}	Reverse Transfer Capacitance	1		60		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 10 \text{ V}, \qquad I_D = 1 \text{ A},$		8	16	ns
t _r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$		8	16	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time	1		14	26	ns
t _f	Turn-Off Fall Time]		3	6	ns
Q _g	Total Gate Charge	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 3.7 \text{ A},$		4	6	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 4.5 V		0.7		nC
Q _{gd}	Gate-Drain Charge	1		1.1		nC

Electric	Electrical Characteristics T _A = 25°C unless otherwise noted						
Symbol	Parameter Test Conditions		Min	Тур	Max	Units	
Drain-Sc	Drain–Source Diode Characteristics and Maximum Ratings						
Is	Maximum Continuous Drain-Sour	nuous Drain-Source Diode Forward Current			1.1	Α	
V_{SD}	Drain–Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 1.1 A (Note 2)		0.7	1.2	V	
t _{rr}	Diode Reverse Recovery Time	I _F = 3.7 A,		11		ns	
Qrr	Diode Reverse Recovery Charge	dI _F /dt = 100 A/μs		2		nC	

Notes

- 1. R_{0,JA} is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,JC} is guaranteed by design while R_{0,JA} is determined by the user's board design.
 - (a) R $_{\rm 0JA}$ = 86°C/W when mounted on a 1in 2 pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
 - (b) R_{0JA} = 173°C/W when mounted on a minimum pad of 2 oz copper
 - (c) $R_{0JA} = 69^{\circ}$ C/W when mounted on a 1in² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
 - (d) $R_{\theta JA}$ = 151°C/W when mounted on a minimum pad of 2 oz copper



Scale 1 : 1 on letter size paper

- **2.** Pulse Test: Pulse Width < 300μ s, Duty Cycle < 2.0%
- 3. The diode connected between the gate and source serves only protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics

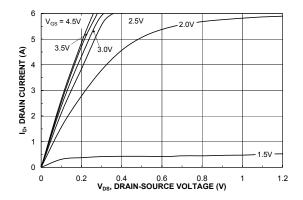


Figure 1. On-Region Characteristics.

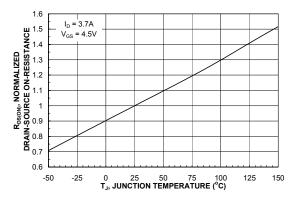


Figure 3. On-Resistance Variation with Temperature.

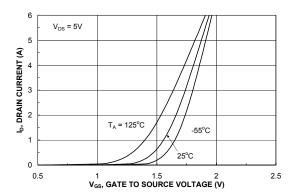


Figure 5. Transfer Characteristics.

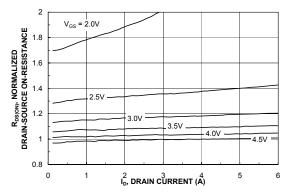


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

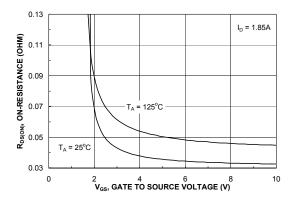


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

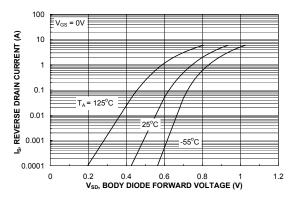
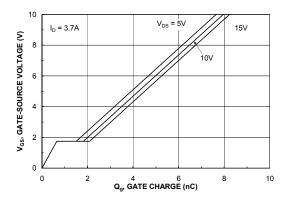


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



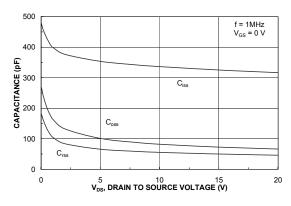
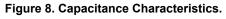
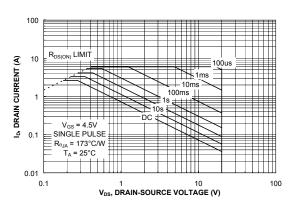


Figure 7. Gate Charge Characteristics.





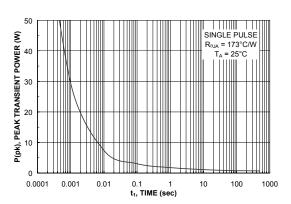


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

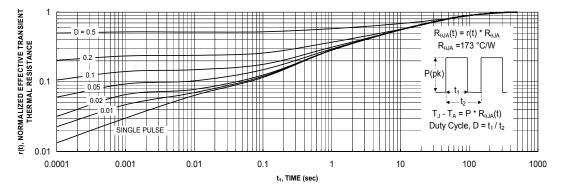
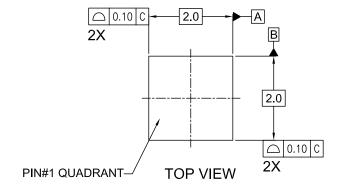
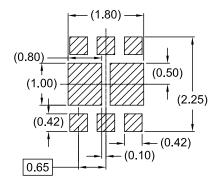


Figure 11. Transient Thermal Response Curve.

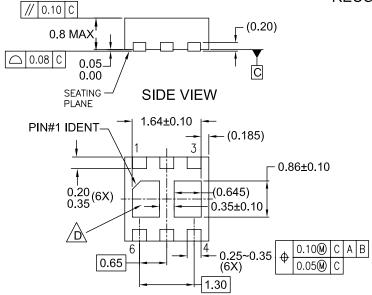
Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN



BOTTOM VIEW

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC EXCEPT AS NOTED.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- NON-JEDEC DUAL DAP
- E. DRAWING FILE NAME : MLP06Jrev3





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